



# ***AOS Semiconductor Product Reliability Report***

**AO4620/AO4620L, rev B**

**Plastic Encapsulated Device**

**ALPHA & OMEGA Semiconductor, Inc**

**495 Mercury Drive  
Sunnyvale, CA 94085  
U.S.**

**Tel: (408) 830-9742**

**[www.aosmd.com](http://www.aosmd.com)**

**Jun 11, 2008**

This AOS product reliability report summarizes the qualification result for AO4620. Accelerated environmental tests are performed on a specific sample size, and then followed by electrical test at end point. Review of final electrical test result confirms that AO4620 passes AOS quality and reliability requirements. The released product will be categorized by the process family and be monitored on a quarterly basis for continuously improving the product quality.

**Table of Contents:**

- I. Product Description
- II. Package and Die information
- III. Environmental Stress Test Summary and Result
- IV. Reliability Evaluation
- V. Quality Assurance Information

**I. Product Description:**

The AO4620/L uses advanced trench technology MOSFETs to provide excellent  $R_{DS(ON)}$  and low gate charge. The complementary MOSFETs may be used in inverter and other applications. AO4620 and AO4620L are electrically identical.

-RoHS Compliant

-AO4620L is Halogen Free

<b>Absolute Maximum Ratings <math>T_A=25^{\circ}\text{C}</math> unless otherwise noted</b>					
Parameter	Symbol	Max n-ch	Max p-ch	Units	
Drain-Source Voltage	$V_{DS}$	30	-30	V	
Gate-Source Voltage	$V_{GS}$	$\pm 20$	$\pm 20$	V	
Continuous Drain Current	$T_A=25^{\circ}\text{C}$	$I_D$	7.2	-5.3	A
	$T_A=70^{\circ}\text{C}$		6.2	-4.5	
Pulsed Drain Current	$I_{DM}$	30	-30		
Power Dissipation	$T_A=25^{\circ}\text{C}$	$P_D$	2	2	W
	$T_A=70^{\circ}\text{C}$		1.44	1.44	
Avalanche Current	$I_{AR}$	13	17	A	
Repetitive avalanche energy $L=0.3\text{mH}$	$E_{AR}$	25	43	mJ	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	-55 to 150	$^{\circ}\text{C}$	

<b>Thermal Characteristics n-ch and p-ch</b>					
Parameter	Symbol	Typ	Max	Units	
Maximum Junction-to-Ambient	$R_{\theta JA}$	50	62.5	$T \leq 10\text{s}$	$^{\circ}\text{C/W}$
Maximum Junction-to-Ambient					
Maximum Junction-to-Lead	$R_{\theta JL}$	32	40	Steady-State	$^{\circ}\text{C/W}$

## II. Die / Package Information:

	<b>AO4620</b>	<b>AO4620L (Green Compound)</b>
<b>Process</b>	Standard sub-micron Low voltage N/P channel	Standard sub-micron Low voltage N/P channel
<b>Package Type</b>	8 leads SOIC	8 leads SOIC
<b>Lead Frame</b>	Cu, D/pad, Ag spot	Cu, D/pad, Ag spot
<b>Die Attach</b>	Ag epoxy	Ag epoxy
<b>Bond wire</b>	G: 1.3mils Au; S: 2mils Cu	G: 1.3mils Au; S: 2mils Cu
<b>Mold Material</b>	Epoxy resin with silica filler	Epoxy resin with silica filler
<b>Filler % (Spherical/Flake)</b>	90/10	100/0
<b>Flammability Rating</b>	UL-94 V-0	UL-94 V-0
<b>Backside Metallization</b>	Ti / Ni / Ag	Ti / Ni / Ag
<b>Moisture Level</b>	Up to Level 1 *	Up to Level 1*

Note \* based on info provided by assembler and mold compound supplier

## III. Result of Reliability Stress for AO4620 (Standard) & AO4620L (Green)

Test Item	Test Condition	Time Point	Lot Attribution	Total Sample size	Number of Failures
Solder Reflow Precondition	Standard: 1hr PCT+3 cycle reflow@260°C Green: 168hr 85°C /85%RH +3 cycle reflow@260°C	0hr	Standard: 83 lots Green: 29 lots	17380 pcs	0
HTGB	Temp = 150°C , Vgs=100% of Vgsmax	168 / 500 hrs 1000 hrs	2 lots  (Note A*)	164 pcs  77+5 pcs / lot	0
HTRB	Temp = 150°C , Vds=80% of Vdsmax	168 / 500 hrs 1000 hrs	2 lots  (Note A*)	164 pcs  77+5 pcs / lot	0
HAST	130 +/- 2°C , 85%RH, 33.3 psi, Vgs = 80% of Vgs max	100 hrs	Standard: 81 lots Green: 16 lots  (Note B**)	5335 pcs  50+5 pcs / lot	0
Pressure Pot	121°C , 29.7 psi , 100%RH	96 hrs	Standard: 83 lots Green: 20 lots  (Note B**)	5665 pcs  50+5 pcs / lot	0
Temperature Cycle	-65°C to 150°C , air to air	250 / 500 cycles	Standard: 87 lots Green: 29 lots  (Note B**)	6380 pcs  50+5 pcs / lot	0

### III. Result of Reliability Stress for AO4620 (Standard) & AO4620L (Green)

Continues

DPA	Internal Vision Cross-section X-ray	NA	5	5	0
			5	5	
			5	5	
CSAM		NA	5	5	0
Bond Integrity	Room Temp 150°C bake 150°C bake	0hr	40	40 wires	0
		250hr	40	40 wires	
		500hr	40	40 wires	
Solderability	245°C	5 sec	15	15 leads	0

**Note A:** The HTGB and HTRB reliability data presents total of available AO4620 and AO4620L burn-in data up to the published date.

**Note B:** The pressure pot, temperature cycle and HAST reliability data for AO4620 and AO4620L comes from the AOS generic package qualification data.

### IV. Reliability Evaluation

**FIT rate (per billion): 21.6**

**MTTF = 5284 years**

In general, 500 hrs of HTGB, 150 deg C accelerated stress testing is equivalent to 15 years of lifetime at 55 deg C operating conditions (by applying the Arrhenius equation with an activation energy of 0.7eV and 60% of upper confidence level on the failure rate calculation). AOS reliability group also routinely monitors the product reliability up to 1000 hr at and performs the necessary failure analysis on the units failed for reliability test(s).

The presentation of FIT rate for the individual product reliability is restricted by the actual burn-in sample size of the selected product (AO4620). Failure Rate Determination is based on JEDEC Standard JESD 85. FIT means one failure per billion hours.

$$\text{Failure Rate} = \text{Chi}^2 \times 10^9 / [2 (N) (H) (Af)] = 1.83 \times 10^9 / [2 (2 \times 164) (500) (258)] = 21.6$$

$$\text{MTTF} = 10^9 / \text{FIT} = 4.62 \times 10^7 \text{hrs} = 5284 \text{ years}$$

**Chi<sup>2</sup>** = Chi Squared Distribution, determined by the number of failures and confidence interval

**N** = Total Number of units from HTRB and HTGB tests

**H** = Duration of HTRB/HTGB testing

**Af** = Acceleration Factor from Test to Use Conditions (Ea = 0.7eV and Tuse = 55°C)

$$\text{Acceleration Factor [Af]} = \text{Exp} [Ea / k (1/Tj u - 1/Tj s)]$$

**Acceleration Factor ratio list:**

	55 deg C	70 deg C	85 deg C	100 deg C	115 deg C	130 deg C	150 deg C
<b>Af</b>	<b>258</b>	<b>87</b>	<b>32</b>	<b>13</b>	<b>5.64</b>	<b>2.59</b>	<b>1</b>

**Tj s** = Stressed junction temperature in degree (Kelvin), K = C+273.16

**Tj u** = The use junction temperature in degree (Kelvin), K = C+273.16

**k** = Boltzmann's constant, 8.617164 X 10<sup>-5</sup>eV / K



## V. Quality Assurance Information

Acceptable Quality Level for outgoing inspection: **0.1%** for electrical and visual.

Guaranteed Outgoing Defect Rate: **< 25 ppm**

Quality Sample Plan: conform to **Mil-Std-105D**